

L Number	Hits	Search Text	DB	Time stamp
1	25	((control\$5 program\$5 adjust\$4 variable) with transistor with (resist\$4 imped\$4)) and ((single near3 event near3 upset) or SEU)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34
2	51	((single near3 event near3 upset) or SEU) and ((resist\$4 imped\$5) near2 value)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34
3	61	((single near3 event near3 upset) SEU)) and ohm	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34
4	30	((single near3 event near3 upset) SEU) and ((var\$5 program\$5 adjust\$4) near3 (impedance resistance))	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34
5	19	((single near3 event near3 upset) SEU) near5 (resist\$3 imped\$3)) and (transistor near3 resistor)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34
6	6	((single near3 event near3 upset) SEU) near5 (resist\$3 imped\$3)) and (resist\$3 adj transistor)	US-PGPUB; EPO; JPO; DERWENT; IBM TDB USPAT;	2004/07/15 20:34